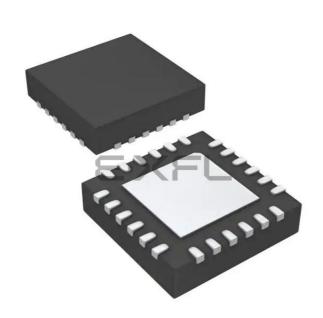
# E·XFL

### NXP USA Inc. - MKL05Z8VFK4 Datasheet



Welcome to E-XFL.COM

#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

#### Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I <sup>2</sup> C, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, LVD, POR, PWM, WDT
Number of I/O	22
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 12x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-VFQFN Exposed Pad
Supplier Device Package	24-QFN (4x4)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mkl05z8vfk4

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

# 1 Ordering parts

## 1.1 Determining valid orderable parts

Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to www.freescale.com and perform a part number search for the following device numbers: PKL05 and MKL05

# 2 Part identification

### 2.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

# 2.2 Format

Part numbers for this device have the following format:

Q KL## A FFF R T PP CC N

# 2.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	<ul> <li>M = Fully qualified, general market flow</li> <li>P = Prequalification</li> </ul>
KL##	Kinetis family	• KL05
A	Key attribute	• Z = Cortex-M0+
FFF	Program flash memory size	<ul> <li>8 = 8 KB</li> <li>16 = 16 KB</li> <li>32 = 32 KB</li> </ul>
R	Silicon revision	<ul> <li>(Blank) = Main</li> <li>A = Revision after main</li> </ul>

Table continues on the next page ...

Terminology and guidelines

Field	Description	Values
Т	Temperature range (°C)	• V = -40 to 105
PP	Package identifier	<ul> <li>FK = 24 QFN (4 mm x 4 mm)</li> <li>LC = 32 LQFP (7 mm x 7 mm)</li> <li>FM = 32 QFN (5 mm x 5 mm)</li> <li>LF = 48 LQFP (7 mm x 7 mm)</li> </ul>
CC	Maximum CPU frequency (MHz)	• 4 = 48 MHz
N	Packaging type	<ul> <li>R = Tape and reel</li> <li>(Blank) = Trays</li> </ul>

### 2.4 Example

This is an example part number:

MKL05Z8VLC4

# 3 Terminology and guidelines

# 3.1 Definition: Operating requirement

An *operating requirement* is a specified value or range of values for a technical characteristic that you must guarantee during operation to avoid incorrect operation and possibly decreasing the useful life of the chip.

### 3.1.1 Example

This is an example of an operating requirement, which you must meet for the accompanying operating behaviors to be guaranteed:

Symbol	Description	Min.	Max.	Unit
V <sub>DD</sub>	1.0 V core supply voltage	0.9	1.1	V

### 3.7 Guidelines for ratings and operating requirements

Follow these guidelines for ratings and operating requirements:

- Never exceed any of the chip's ratings.
- During normal operation, don't exceed any of the chip's operating requirements.
- If you must exceed an operating requirement at times other than during normal operation (for example, during power sequencing), limit the duration as much as possible.

## 3.8 Definition: Typical value

A *typical value* is a specified value for a technical characteristic that:

- Lies within the range of values specified by the operating behavior
- Given the typical manufacturing process, is representative of that characteristic during operation when you meet the typical-value conditions or other specified conditions

Typical values are provided as design guidelines and are neither tested nor guaranteed.

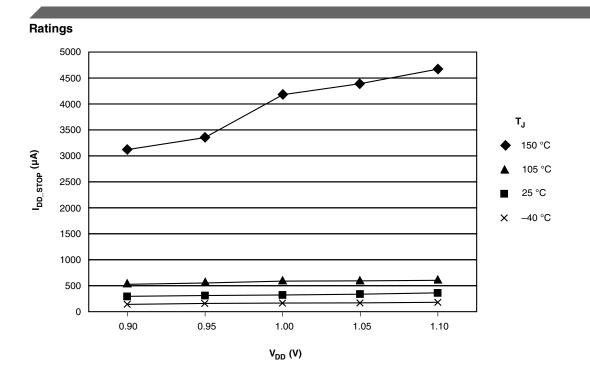
### 3.8.1 Example 1

This is an example of an operating behavior that includes a typical value:

Symbol	Description	Min.	Тур.	Max.	Unit
I <sub>WP</sub>	Digital I/O weak pullup/pulldown current	10	70	130	μΑ

### 3.8.2 Example 2

This is an example of a chart that shows typical values for various voltage and temperature conditions:



# 3.9 Typical Value Conditions

Typical values assume you meet the following conditions (or other conditions as specified):

Symbol	Description	Value	Unit
T <sub>A</sub>	Ambient temperature	25	C°
V <sub>DD</sub>	3.3 V supply voltage	3.3	V

# 4 Ratings

# 4.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T <sub>STG</sub>	Storage temperature	-55	150	°C	1
T <sub>SDR</sub>	Solder temperature, lead-free	_	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, High Temperature Storage Life.

2. Determined according to IPC/JEDEC Standard J-STD-020, Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices.

Symbol	Description	Min.	Max.	Unit	Notes
I <sub>ICIO</sub>	I/O pin DC injection current — single pin				1
	<ul> <li>V<sub>IN</sub> &lt; V<sub>SS</sub>-0.3V (Negative current injection)</li> </ul>			mA	
	<ul> <li>V<sub>IN</sub> &gt; V<sub>DD</sub>+0.3V (Positive current injection)</li> </ul>	-3	—		
		—	+3		
I <sub>ICcont</sub>	Contiguous pin DC injection current —regional limit, includes sum of negative injection currents or sum of positive injection currents of 16 contiguous pins				
	Negative current injection	-25	—	mA	
	Positive current injection	—	+25		
V <sub>RAM</sub>	V <sub>DD</sub> voltage required to retain RAM	1.2	_	V	

Table 1. Voltage and current operating requirements (continued)

All analog pins are internally clamped to V<sub>SS</sub> and V<sub>DD</sub> through ESD protection diodes. If V<sub>IN</sub> is greater than V<sub>AIO\_MIN</sub> (=V<sub>SS</sub>-0.3V) and V<sub>IN</sub> is less than V<sub>AIO\_MAX</sub>(=V<sub>DD</sub>+0.3V) is observed, then there is no need to provide current limiting resistors at the pads. If these limits cannot be observed then a current limiting resistor is required. The negative DC injection current limiting resistor is calculated as R=(V<sub>AIO\_MIN</sub>-V<sub>IN</sub>)/II<sub>IC</sub>I. The positive injection current limiting resistor is calculated the larger of these two calculated resistances.

# 5.2.2 LVD and POR operating requirements

Table 2. V<sub>DD</sub> supply LVD and POR operating requirements

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
V <sub>POR</sub>	Falling V <sub>DD</sub> POR detect voltage	0.8	1.1	1.5	V	
$V_{LVDH}$	Falling low-voltage detect threshold — high range (LVDV=01)	2.48	2.56	2.64	V	
	Low-voltage warning thresholds — high range					1
$V_{LVW1H}$	Level 1 falling (LVWV=00)	2.62	2.70	2.78	v	
$V_{LVW2H}$	Level 2 falling (LVWV=01)	2.72	2.80	2.88	V	
V <sub>LVW3H</sub>	Level 3 falling (LVWV=10)	2.82	2.90	2.98	V	
$V_{LVW4H}$	Level 4 falling (LVWV=11)	2.92	3.00	3.08	v	
V <sub>HYSH</sub>	Low-voltage inhibit reset/recover hysteresis — high range	_	±60	_	mV	
V <sub>LVDL</sub>	Falling low-voltage detect threshold — low range (LVDV=00)	1.54	1.60	1.66	V	
	Low-voltage warning thresholds — low range					1
$V_{LVW1L}$	Level 1 falling (LVWV=00)	1.74	1.80	1.86	V	
$V_{LVW2L}$	Level 2 falling (LVWV=01)	1.84	1.90	1.96	V	
V <sub>LVW3L</sub>	Level 3 falling (LVWV=10)	1.94	2.00	2.06	v	
$V_{LVW4L}$	Level 4 falling (LVWV=11)	2.04	2.10	2.16	v	
V <sub>HYSL</sub>	Low-voltage inhibit reset/recover hysteresis — low range	_	±40	-	mV	

Table continues on the next page ...

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
I <sub>DD_RUN</sub>	Run mode current - 48 MHz core / 24 MHz bus and flash, all peripheral clocks enabled, code of while(1) loop executing from flash					2, 3
	• at 3.0 V					
	• at 25 °C		5.6	6.8	mA	
	• at 125 °C	_	6	7.2	mA	
I <sub>DD_WAIT</sub>	Wait mode current - core disabled / 48 MHz system / 24 MHz bus / flash disabled (flash doze enabled), all peripheral clocks disabled • at 3.0 V	_	3.0	4.2	mA	2
I <sub>DD_WAIT</sub>	Wait mode current - core disabled / 24 MHz system / 24 MHz bus / flash disabled (flash doze enabled), all peripheral clocks disabled • at 3.0 V	_	2.4	3.36	mA	2
I <sub>DD_PSTOP2</sub>	Stop mode current with partial stop 2 clocking option - core and system disabled / 10.5 MHz bus • at 3.0 V		2.25	3.38	mA	2
DD_VLPRCO	Very-low-power run mode current in compute operation - 4 MHz core / 0.8 MHz flash / bus clock disabled, code of while(1) loop executing from flash • at 3.0 V		182	522	μA	4
I <sub>DD_VLPR</sub>	Very-low-power run mode current - 4 MHz core / 0.8 MHz bus and flash, all peripheral clocks disabled, code of while(1) loop executing from flash • at 3.0 V	_	213.33	577.8	μΑ	4
I <sub>DD_VLPR</sub>	Very-low-power run mode current - 4 MHz core / 0.8 MHz bus and flash, all peripheral clocks enabled, code of while(1) loop executing from flash • at 3.0 V		242.8	631.8	μΑ	3, 4
I <sub>DD_VLPW</sub>	Very-low-power wait mode current - core disabled / 4 MHz system / 0.8 MHz bus / flash disabled (flash doze enabled), all peripheral clocks disabled • at 3.0 V	_	106.1	399.42	μΑ	4

### Table 5. Power consumption operating behaviors (continued)

Table continues on the next page ...

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
I <sub>DD_STOP</sub>	Stop mode current • at 3.0 V					
	• at 3.0 v • at 25 °C					
	• at 25 °C	_	273	441		
		_	281.2	620	μA	
	• at 70 °C	_	301.6	647.64		
	• at 85 °C	_	331	710.64		
	• at 105 °C	_	406.6	1001.84		
I <sub>DD_VLPS</sub>	Very-low-power stop mode current • at 3.0 V					
	• at 25 °C	_	3.08	16.01		
	• at 50 °C	_	5.46	34.73	μA	
	• at 70 °C	_	12.08	46.73	P	
	• at 85 °C	_	22.89	77.37		
	• at 105 °C	_	53.24	190.28		
I <sub>DD_LLS</sub>	Low-leakage stop mode current • at 3.0 V					
	• at 25 °C		47	0.00		
	• at 50 °C	_	1.7	3.69		
	• at 70 °C	_	3	22	μA	
	• at 85 °C	_	5.8	28.19		
	• at 105 °C	_	10.4	40.29		
		—	24	65.5		
I <sub>DD_VLLS3</sub>	<ul><li>Very-low-leakage stop mode 3 current</li><li>at 3.0 V</li></ul>				μA	
	• at 25 °C		1.3	3		
	• at 50 °C		2.3	11.04		
	• at 70 °C		4.4	13.68		
	• at 85 °C		8	20.14		
	• at 105 °C		18.6	37.82		
I <sub>DD_VLLS1</sub>	Very-low-leakage stop mode 1 current • at 3.0 V		10.0	07.02		
	• at 25°C					
	• at 50°C	-	0.78	1.6		
	• at 70°C		1.5	13.61	μA	
	• at 85°C		3.3	15.59		
	• at 105°C	-	6.3	16.68		
	- at 103 0		15.2	26.40		

Table 5. Power consumption operating behaviors (continued)

Table continues on the next page...

#### General

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
I <sub>DD_VLLS0</sub>	Very-low-leakage stop mode 0 current (SMC_STOPCTRL[PORPO] = 0) • at 3.0 V					
	• at 25 °C					
	• at 50 °C	-	449.6	959.2	nA	
	• at 70 °C	—	1200	12155.08		
	• at 85 °C	_	2900	15323.29		
	• at 105 °C	_	5900	16384.55		
		_	14800	26773.45		
I <sub>DD_VLLS0</sub>	Very-low-leakage stop mode 0 current (SMC_STOPCTRL[PORPO] = 1) • at 3.0 V					5
	• at 25 °C					
	• at 50 °C	—	221.7	894.24	nA	
	• at 70 °C	—	1000	3784.55		
	• at 85 °C	-	2600	12018.39		
	• at 105 °C	-	5600	18722.23		
		_	14400	24665.06		

### Table 5. Power consumption operating behaviors (continued)

- 1. The analog supply current is the sum of the active or disabled current for each of the analog modules on the device. See each module's specification for its supply current.
- 2. MCG configured for FEI mode.
- 3. Incremental current consumption from peripheral activity is not included.
- 4. MCG configured for BLPI mode.
- 5. No brownout

Table 6.	Low power mode	peripheral adders -	<ul> <li>typical value</li> </ul>
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Symbol	Description		Temperature (°C)				Unit	
		-40	25	50	70	85	105	
I <sub>IREFSTEN4MHz</sub>	4 MHz internal reference clock (IRC) adder. Measured by entering STOP or VLPS mode with 4 MHz IRC enabled.	56	56	56	56	56	56	μA
IIREFSTEN32KHz	32 kHz internal reference clock (IRC) adder. Measured by entering STOP mode with the 32 kHz IRC enabled.	52	52	52	52	52	52	μA
I <sub>EREFSTEN4MHz</sub>	External 4 MHz crystal clock adder. Measured by entering STOP or VLPS mode with the crystal enabled.	206	228	237	245	251	258	uA

Table continues on the next page...

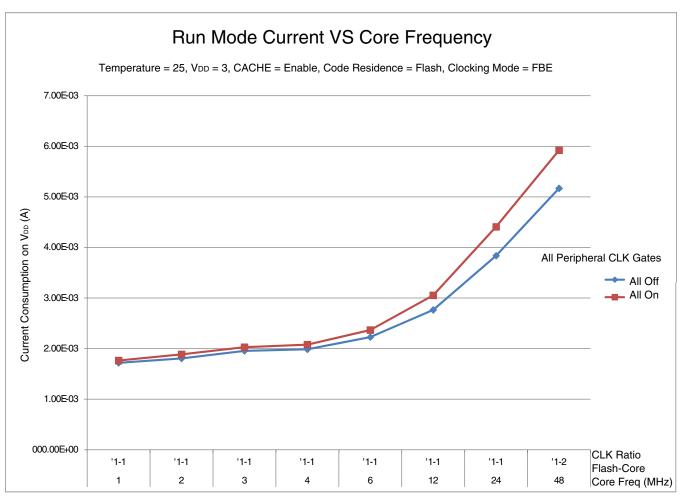


Figure 2. Run mode supply current vs. core frequency

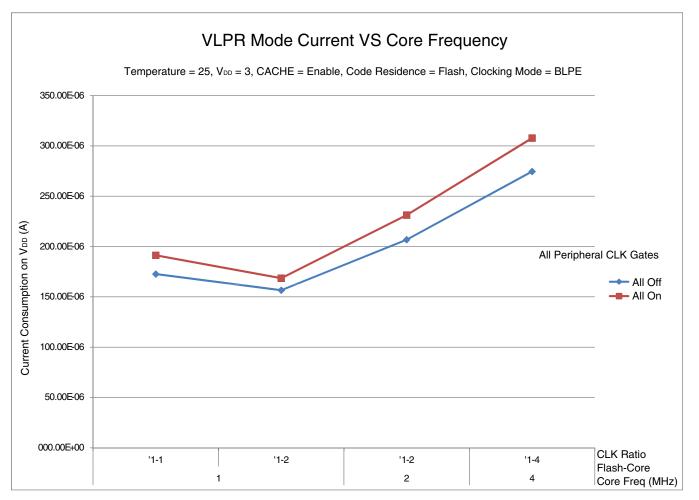


Figure 3. VLPR mode current vs. core frequency

### 5.2.6 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

- 1. Go to www.freescale.com.
- 2. Perform a keyword search for "EMC design."

### 5.2.7 Capacitance attributes

Table 7. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C <sub>IN_A</sub>	Input capacitance: analog pins	_	7	pF
C <sub>IN_D</sub>	Input capacitance: digital pins		7	pF

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
$V_{DD}$	Supply voltage	1.71	_	3.6	V	
IDDOSC	Supply current — low-power mode (HGO=0)					1
	• 32 kHz	—	500	_	nA	
	• 4 MHz	—	200	—	μA	
	• 8 MHz (RANGE=01)	—	300	—	μA	
	• 16 MHz	—	950	—	μA	
	• 24 MHz	—	1.2	—	mA	
	• 32 MHz	—	1.5	—	mA	
IDDOSC	Supply current — high gain mode (HGO=1)					1
	• 32 kHz	—	25	_	μA	
	• 4 MHz	—	400	_	μA	
	• 8 MHz (RANGE=01)	—	500	_	μA	
	• 16 MHz	—	2.5	_	mA	
	• 24 MHz	—	3	_	mA	
	• 32 MHz	—	4	_	mA	
C <sub>x</sub>	EXTAL load capacitance					2, 3
Cy	XTAL load capacitance	_	_	_		2, 3
R <sub>F</sub>	Feedback resistor — low-frequency, low-power mode (HGO=0)	_	_	_	MΩ	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	—	10	_	MΩ	
	Feedback resistor — high-frequency, low-power mode (HGO=0)	_	_	—	MΩ	
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	—	1	_	MΩ	
$R_S$	Series resistor — low-frequency, low-power mode (HGO=0)	—	_	—	kΩ	
	Series resistor — low-frequency, high-gain mode (HGO=1)	_	200	—	kΩ	
	Series resistor — high-frequency, low-power mode (HGO=0)	_	_	—	kΩ	
	Series resistor — high-frequency, high-gain mode (HGO=1)					
		_	0	_	kΩ	

### 6.3.2.1 Oscillator DC electrical specifications Table 12. Oscillator DC electrical specifications

Table continues on the next page...

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
V <sub>pp</sub> <sup>5</sup>	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, low-power mode (HGO=0)	—	0.6	_	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, high-gain mode (HGO=1)		V <sub>DD</sub>	_	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, low-power mode (HGO=0)	—	0.6	_	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, high-gain mode (HGO=1)	_	V <sub>DD</sub>		V	

 Table 12.
 Oscillator DC electrical specifications (continued)

- 1. V<sub>DD</sub>=3.3 V, Temperature =25 °C
- 2. See crystal or resonator manufacturer's recommendation
- 3. C<sub>x</sub>,C<sub>y</sub> can be provided by using the integrated capacitors when the low frequency oscillator (RANGE = 00) is used. For all other cases external capacitors must be used.
- 4. When low power mode is selected, R<sub>F</sub> is integrated and must not be attached externally.
- 5. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other devices.

### 6.3.2.2 Oscillator frequency specifications

### Table 13. Oscillator frequency specifications

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
f <sub>osc_lo</sub>	Oscillator crystal or resonator frequency — low frequency mode (MCG_C2[RANGE]=00)	32	-	40	kHz	
f <sub>osc_hi_1</sub>	Oscillator crystal or resonator frequency — high frequency mode (low range) (MCG_C2[RANGE]=01)	3	_	8	MHz	
f <sub>osc_hi_2</sub>	Oscillator crystal or resonator frequency — high frequency mode (high range) (MCG_C2[RANGE]=1x)	8	_	32	MHz	
f <sub>ec_extal</sub>	Input clock frequency (external clock mode)	—	—	48	MHz	1, 2
t <sub>dc_extal</sub>	Input clock duty cycle (external clock mode)	40	50	60	%	
t <sub>cst</sub>	Crystal startup time — 32 kHz low-frequency, low-power mode (HGO=0)	_		-	ms	3, 4
	Crystal startup time — 32 kHz low-frequency, high-gain mode (HGO=1)	_		-	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), low-power mode (HGO=0)	_	0.6	_	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), high-gain mode (HGO=1)	—	1	—	ms	

- 1. Other frequency limits may apply when external clock is being used as a reference for the FLL or PLL.
- 2. When transitioning from FBE to FEI mode, restrict the frequency of the input clock so that, when it is divided by FRDIV, it remains within the limits of the DCO input clock frequency.

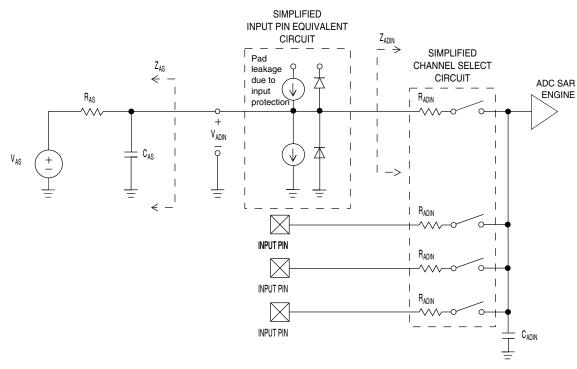


Figure 6. ADC input impedance equivalency diagram

### 6.6.1.2 12-bit ADC electrical characteristics Table 19. 12-bit ADC characteristics (V<sub>REFH</sub> = V<sub>DDA</sub>, V<sub>REFL</sub> = V<sub>SSA</sub>)

Symbol	Description	Conditions <sup>1</sup>	Min.	Typ. <sup>2</sup>	Max.	Unit	Notes
I <sub>DDA_ADC</sub>	Supply current		0.215	—	1.7	mA	3
	ADC	• ADLPC = 1, ADHSC = 0	1.2	2.4	3.9	MHz	$t_{ADACK} = 1/$
	asynchronous clock source	• ADLPC = 1, ADHSC = 1	2.4	4.0	6.1	MHz	f <sub>ADACK</sub>
f <sub>ADACK</sub>		• ADLPC = 0, ADHSC = 0	3.0	5.2	7.3	MHz	
		• ADLPC = 0, ADHSC = 1	4.4	6.2	9.5	MHz	
	Sample Time	See Reference Manual chapter	for sample t	imes			
TUE	Total unadjusted	12-bit modes		±4	±6.8	LSB <sup>4</sup>	5
	error	<ul> <li>&lt;12-bit modes</li> </ul>	—	±1.4	±2.1		
DNL	Differential non-	12-bit modes		±0.7	-1.1 to +1.9	LSB <sup>4</sup>	5
	linearity				-0.3 to 0.5		
		<ul> <li>&lt;12-bit modes</li> </ul>	—	±0.2			
INL	Integral non-	12-bit modes		±1.0	-2.7 to +1.9	LSB <sup>4</sup>	5
	linearity				-0.7 to +0.5		
		<ul> <li>&lt;12-bit modes</li> </ul>	—	±0.5			
E <sub>FS</sub>	Full-scale error	12-bit modes	_	-4	-5.4	LSB <sup>4</sup>	V <sub>ADIN</sub> =
		<ul> <li>&lt;12-bit modes</li> </ul>	_	-1.4	-1.8		V <sub>DDA</sub>
							5

Table continues on the next page ...

Symbol	Description	Conditions <sup>1</sup>	Min.	Typ. <sup>2</sup>	Max.	Unit	Notes
E <sub>Q</sub>	Quantization error	12-bit modes	_	_	±0.5	LSB <sup>4</sup>	
EIL	Input leakage error			I <sub>In</sub> × R <sub>AS</sub>		mV	I <sub>In</sub> = leakage current (refer to the MCU's voltage and current operating ratings)
	Temp sensor slope	Across the full temperature range of the device	—	1.715		mV/°C	
V <sub>TEMP25</sub>	Temp sensor voltage	25 °C	_	719	—	mV	

### Table 19. 12-bit ADC characteristics ( $V_{REFH} = V_{DDA}$ , $V_{REFL} = V_{SSA}$ ) (continued)

- 1. All accuracy numbers assume the ADC is calibrated with  $V_{REFH} = V_{DDA}$
- Typical values assume V<sub>DDA</sub> = 3.0 V, Temp = 25°C, f<sub>ADCK</sub> = 2.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
- The ADC supply current depends on the ADC conversion clock speed, conversion rate and the ADLPC bit (low power). For lowest power operation the ADLPC bit must be set, the HSC bit must be clear with 1 MHz ADC conversion clock speed.
- 4. 1 LSB =  $(V_{REFH} V_{REFL})/2^N$
- 5. ADC conversion clock < 16 MHz, Max hardware averaging (AVGE = %1, AVGS = %11)

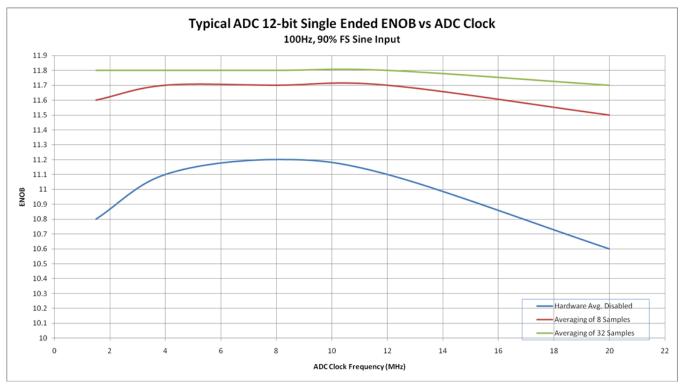


Figure 7. Typical ENOB vs. ADC\_CLK for 12-bit single-ended mode

### 6.6.2 CMP and 6-bit DAC electrical specifications

Table 20.	Comparator	<sup>·</sup> and 6-bit DAC	electrical s	pecifications
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Symbol	Description	Min.	Тур.	Max.	Unit
V <sub>DD</sub>	Supply voltage	1.71	_	3.6	V
I <sub>DDHS</sub>	Supply current, high-speed mode (EN = 1, PMODE = 1)	_	_	200	μA
I <sub>DDLS</sub>	Supply current, low-speed mode (EN = 1, PMODE = 0)	_	_	20	μA
V <sub>AIN</sub>	Analog input voltage	V <sub>SS</sub>	_	V <sub>DD</sub>	V
V <sub>AIO</sub>	Analog input offset voltage	_	_	20	mV
V <sub>H</sub>	Analog comparator hysteresis <sup>1</sup>				
	• CR0[HYSTCTR] = 00	—	5	—	mV
	• CR0[HYSTCTR] = 01	_	10	_	mV
	• CR0[HYSTCTR] = 10	_	20	_	mV
	• CR0[HYSTCTR] = 11	—	30	_	mV
V <sub>CMPOh</sub>	Output high	V <sub>DD</sub> - 0.5		_	V
V <sub>CMPOI</sub>	Output low		_	0.5	V
t <sub>DHS</sub>	Propagation delay, high-speed mode (EN = 1, PMODE = 1)	20	50	200	ns
t <sub>DLS</sub>	Propagation delay, low-speed mode (EN = 1, PMODE = 0)	80	250	600	ns
	Analog comparator initialization delay <sup>2</sup>	_		40	μs
I <sub>DAC6b</sub>	6-bit DAC current adder (enabled)	_	7	—	μA
INL	6-bit DAC integral non-linearity	-0.5		0.5	LSB <sup>3</sup>
DNL	6-bit DAC differential non-linearity	-0.3	_	0.3	LSB

1. Typical hysteresis is measured with input voltage range limited to 0.7 to  $V_{DD}$  – 0.7 V.

2. Comparator initialization delay is defined as the time between software writes to change control inputs (writes to DACEN, VRSEL, PSEL, MSEL, VOSEL) and the comparator output settling to a stable level.

3. 1 LSB =  $V_{reference}/64$ 

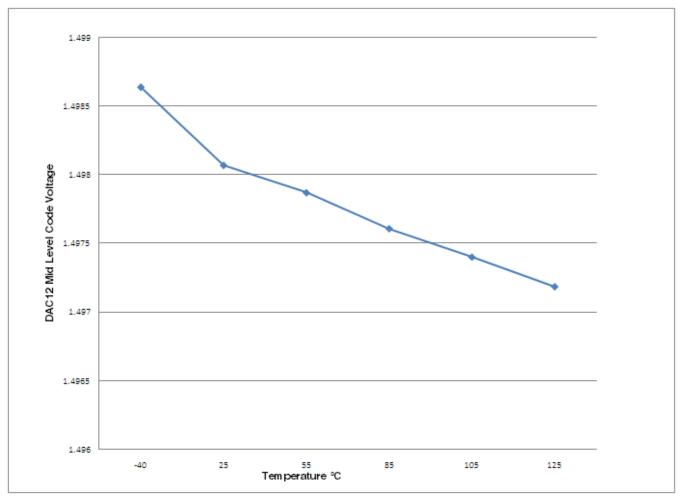


Figure 11. Offset at half scale vs. temperature

# 6.7 Timers

See General switching specifications.

# 6.8 Communication interfaces

### 6.8.1 SPI switching specifications

The Serial Peripheral Interface (SPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The following tables provide timing characteristics for classic SPI timing modes. See the SPI chapter of the chip's Reference Manual for information about the modified transfer formats used for communicating with slower peripheral devices.

#### Peripheral operating requirements and behaviors

All timing is shown with respect to  $20\% V_{DD}$  and  $80\% V_{DD}$  thresholds, unless noted, as well as input signal transitions of 3 ns and a 30 pF maximum load on all SPI pins.

Num.	Symbol	Description	Min.	Max.	Unit	Note
1	f <sub>op</sub>	Frequency of operation	f <sub>periph</sub> /2048	f <sub>periph</sub> /2	Hz	1
2	t <sub>SPSCK</sub>	SPSCK period	2 x t <sub>periph</sub>	2048 x	ns	2
				t <sub>periph</sub>		
3	t <sub>Lead</sub>	Enable lead time	1/2	—	t <sub>SPSCK</sub>	_
4	t <sub>Lag</sub>	Enable lag time	1/2	_	t <sub>SPSCK</sub>	—
5	t <sub>WSPSCK</sub>	Clock (SPSCK) high or low time	t <sub>periph</sub> - 30	1024 x	ns	—
				t <sub>periph</sub>		
6	t <sub>SU</sub>	Data setup time (inputs)	16	_	ns	—
7	t <sub>HI</sub>	Data hold time (inputs)	0	_	ns	—
8	t <sub>v</sub>	Data valid (after SPSCK edge)	_	10	ns	—
9	t <sub>HO</sub>	Data hold time (outputs)	0	_	ns	—
10	t <sub>RI</sub>	Rise time input	—	t <sub>periph</sub> - 25	ns	—
	t <sub>FI</sub>	Fall time input				
11	t <sub>RO</sub>	Rise time output	—	25	ns	—
	t <sub>FO</sub>	Fall time output				

Table 23. SPI master mode timing on slew rate disabled pads

- 1. For SPI0  $f_{periph}$  is the bus clock ( $f_{BUS}$ ).
- 2.  $t_{periph} = 1/f_{periph}$

### Table 24. SPI master mode timing on slew rate enabled pads

Num.	Symbol	Description	Min.	Max.	Unit	Note
1	f <sub>op</sub>	Frequency of operation	f <sub>periph</sub> /2048	f <sub>periph</sub> /2	Hz	1
2	t <sub>SPSCK</sub>	SPSCK period	2 x t <sub>periph</sub>	2048 x t <sub>periph</sub>	ns	2
3	t <sub>Lead</sub>	Enable lead time	1/2		t <sub>SPSCK</sub>	-
4	t <sub>Lag</sub>	Enable lag time	1/2	—	t <sub>SPSCK</sub>	-
5	twspsck	Clock (SPSCK) high or low time	t <sub>periph</sub> - 30	1024 x t <sub>periph</sub>	ns	-
6	t <sub>SU</sub>	Data setup time (inputs)	96	_	ns	_
7	t <sub>HI</sub>	Data hold time (inputs)	0		ns	_
8	t <sub>v</sub>	Data valid (after SPSCK edge)	—	52	ns	_
9	t <sub>HO</sub>	Data hold time (outputs)	0	_	ns	_
10	t <sub>RI</sub>	Rise time input	—	t <sub>periph</sub> - 25	ns	_
	t <sub>FI</sub>	Fall time input				
11	t <sub>RO</sub>	Rise time output	_	36	ns	_
	t <sub>FO</sub>	Fall time output				

1. For SPI0  $f_{\text{periph}}$  is the bus clock (f\_{\text{BUS}}).

2.  $t_{periph} = 1/f_{periph}$ 

# 8.1 KL05 signal multiplexing and pin assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

48 LQFP	32 QFN	32 LQFP	24 QFN	Pin Name	Default	ALT0	ALT1	ALT2	ALT3
1	1	1	1	PTB6/ IRQ_2/ LPTMR0_ALT3	DISABLED	DISABLED	PTB6/ IRQ_2/ LPTMR0_ALT3	TPM0_CH3	TPM_CLKIN1
2	2	2	2	PTB7/ IRQ_3	DISABLED	DISABLED	PTB7/ IRQ_3	TPM0_CH2	
3	_	_	-	PTA14	DISABLED	DISABLED	PTA14		TPM_CLKIN0
4	_	_	_	PTA15	DISABLED	DISABLED	PTA15		CLKOUT
5	3	3	3	VDD	VDD	VDD			
6	4	4	3	VREFH	VREFH	VREFH			
7	5	5	4	VREFL	VREFL	VREFL			
8	6	6	4	VSS	VSS	VSS			
9	7	7	5	PTA3	EXTALO	EXTALO	PTA3	I2C0_SCL	I2C0_SDA
10	8	8	6	PTA4/ LLWU_P0	XTALO	XTALO	PTA4/ LLWU_P0	I2C0_SDA	I2C0_SCL
11	_	_	-	VSS	VSS	VSS			
12	_	_	_	PTB18	DISABLED	DISABLED	PTB18		
13	_	_	-	PTB19	DISABLED	DISABLED	PTB19		
14	9	9	7	PTA5/ LLWU_P1/ RTC_CLK_IN	DISABLED	DISABLED	PTA5/ LLWU_P1/ RTC_CLK_IN	TPM0_CH5	SPI0_SS_b
15	10	10	8	PTA6/ LLWU_P2	DISABLED	DISABLED	PTA6/ LLWU_P2	TPM0_CH4	SPI0_MISO
16	11	11	-	PTB8	ADC0_SE11	ADC0_SE11	PTB8	TPM0_CH3	
17	12	12	_	PTB9	ADC0_SE10	ADC0_SE10	PTB9	TPM0_CH2	
18	_	-	_	PTA16/ IRQ_4	DISABLED	DISABLED	PTA16/ IRQ_4		
19	_	_	-	PTA17/ IRQ_5	DISABLED	DISABLED	PTA17/ IRQ_5		
20	_	-	-	PTA18/ IRQ_6	DISABLED	DISABLED	PTA18/ IRQ_6		
21	13	13	9	PTB10	ADC0_SE9/ TSI0_IN7	ADC0_SE9/ TSI0_IN7	PTB10	TPM0_CH1	
22	14	14	10	PTB11	ADC0_SE8/ TSI0_IN6	ADC0_SE8/ TSI0_IN6	PTB11	TPM0_CH0	
23	15	15	11	PTA7/ IRQ_7/ LLWU_P3	ADC0_SE7/ TSI0_IN5	ADC0_SE7/ TSI0_IN5	PTA7/ IRQ_7/ LLWU_P3	SPI0_MISO	SPI0_MOSI
24	16	16	12	PTB0/ IRQ_8/ LLWU_P4	ADC0_SE6/ TSI0_IN4	ADC0_SE6/ TSI0_IN4	PTB0/ IRQ_8/ LLWU_P4	EXTRG_IN	SPI0_SCK



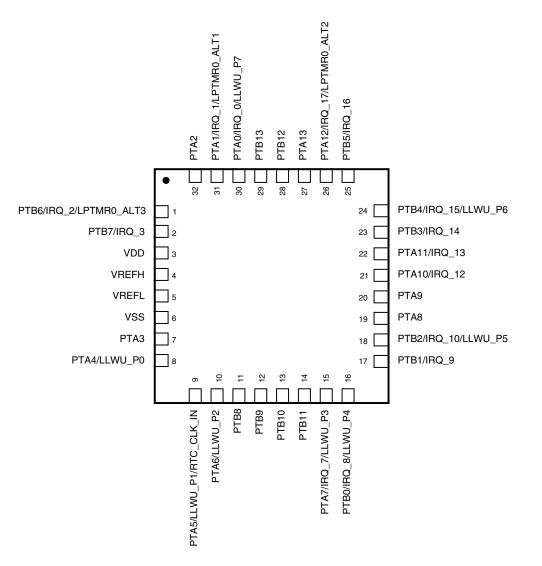


Figure 18. KL05 32-pin QFN pinout diagram

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